

Notice of References Cited

Application/Control No.

10/565,863

Applicant(s)/Patent Under
Reexamination
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Examiner

JOHN Wahnkyo LEE

Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,819,794 B2	11-2004	Inoue, Hitoshi	382/169
	B	US-			
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	E	US-			
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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